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# LINEAR DYNAMICAL SYSTEMS OF THE N-TH ORDER IN RANDOM CONDITIONS

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**Abstract:** In the article, the linear dynamic random model of n-th order described by the random state equation is considered. The method for determining the probabilistic characteristics of a stochastic process which is the solution of that equation, is shown. These characteristics, such as mean values and correlation functions, are determined by auxiliary solutions – the deterministic systems of ordinary differential equations.

**Key words:** moments of stochastic processes, n-th order random system.

#### 1. Introduction

Random dynamical systems are the models of many systems occurring in electrical engineering and electronics [10]. They are usually described by the stochastic differential equations [13]. In the article the method of determining the mean value and the correlation function of the stochastic processes is described, these characteristics being the solutions of linear n-th order random differential equations. The presented results are the generalization of previous works [4, 5, 6, 7, 8, 9, 10] concerning this subject.

## 2. The formalization of the problem.

A random dynamical system described by the state equation is given:

$$\begin{cases} \frac{dX(t)}{dt} = \mathbf{A}X(t) + \mathbf{B}F(t) \\ X(0) = X_0 \end{cases}$$
 (1)

where:  $\mathbf{A}, \mathbf{B}$  — are deterministic matrices,  $\mathbf{X}_0$  — is the random or deterministic vector of initial conditions,  $\mathbf{F}(t)$  — is the random vector of stochastic processes—excitations satisfying the mean-square Lipschitz condition,  $\mathbf{X}(t)$  — is the random vector which is the solution of (in mean-square sense) the equation (1), and the output equation:

$$\mathbf{Y}(t) = \mathbf{C}\mathbf{X}(t) + \mathbf{D}\mathbf{F}(t) \tag{2}$$

where:  $\mathbf{C}, \mathbf{D}$  – are deterministic matrices,  $\mathbf{Y}(t)$  – is the random vector of output stochastic processes.

For solving the equation (1) various methods can be used: the direct method or the method of transformation

equations to the moment equation. To solve the equation (1), the method of moments is used [11].

### 3. Method of moments.

Using the expected value of the operator E [] in the both sides of the equation (1) the deterministic system of differential equations in respect to the vector  $\boldsymbol{\mu}_{X}(t)$  is obtained, which is the expected value of the process  $\mathbf{X}(t)$ :

$$\begin{cases} \frac{d\mu_X(t)}{dt} = \mathbf{A}\mu_X(t) + \mathbf{B}\mu_F(t) \\ \mu_X(0) = \mu_{X0} \end{cases}$$
 (3)

The system (3) is solved by classical methods of mathematical analysis.

Cross correlation of the processes F(t) and X(t) is the function:

$$\mathbf{R}_{FX}(t_1, t_2) = E \left[ \mathbf{F}(t_1) \mathbf{X}^T(t_2) \right]$$
 (4)

Then the next operations are to be performed:

– bilateral transposition of the equation (1) and substitution  $t=t_2$ :

$$\begin{cases} \frac{d\mathbf{X}^{T}(t_{2})}{dt_{2}} = \mathbf{X}^{T}(t_{2})\mathbf{A}^{T} + \mathbf{F}^{T}(t_{2})\mathbf{B}^{T} \\ \mathbf{X}^{T}(0) = \mathbf{X}_{0}^{T} \end{cases}$$
(5)

– multiplying both sides of the equation by the process  $\mathbf{F}(t_1)$ :

$$\begin{cases}
\mathbf{F}(t_1) \frac{d\mathbf{X}^T(t_2)}{dt_2} = \mathbf{F}(t_1) \mathbf{X}^T(t_2) \mathbf{A}^T + \\
+ \mathbf{F}(t_1) \mathbf{F}^T(t_2) \mathbf{B}^T
\end{cases} (6)$$

$$\mathbf{F}(t_1) \mathbf{X}^T(0) = \mathbf{F}(t_1) \mathbf{X}_0^T$$

- applying the expected value of the operator to the result of the previous step. So, as a result the deterministic equation system is obtained:

$$\begin{cases}
\frac{\partial \mathbf{R}_{FX}(t_1, t_2)}{\partial t_2} = \mathbf{R}_{FX}(t_1, t_2) \mathbf{A}^T + \\
+ \mathbf{R}_F(t_1, t_2) \mathbf{B}^T
\end{cases} (7)$$

$$\mathbf{R}_{FX}(t_1, 0) = \mu_F(t_1) \mu_{X_0}^T$$

In system (7), the variable  $t_1$  is treated as a parameter. For a fixed value of the variable  $t_1$ , this system is solved by classical methods.

Autocorrelation of the process  $\mathbf{X}(t)$  is the function:

$$\mathbf{R}_{X}(t_{1},t_{2}) = E\left[\mathbf{X}(t_{1})\mathbf{X}^{T}(t_{2})\right]. \tag{8}$$

Using the described procedure, in a similar way one can obtain a deterministic system of ordinary differential equations in respect to the vector function  $\mathbf{R}_X(t_1, t_2)$  which is the autocorrelation function of the process  $\mathbf{X}(t)$ :

$$\begin{cases}
\frac{\partial \mathbf{R}_{X}(t_{1}, t_{2})}{\partial t_{1}} = \mathbf{A} \mathbf{R}_{X}(t_{1}, t_{2}) + \\
+ \mathbf{B} \mathbf{R}_{FX}(t_{1}, t_{2})
\end{cases}$$

$$\mathbf{R}_{X}(0, t_{2}) = E[\mathbf{X}_{0} \mathbf{X}^{T}(t_{2})]$$
(9)

In system (9), the variable  $t_1$  is treated as a parameter. System (9) is treated as a deterministic ordinary differential equation.

If the initial condition of the system (9) is a vector of real numbers, the system (9) can be simplified to the form:

$$\begin{cases}
\frac{\partial \mathbf{R}_{X}(t_{1}, t_{2})}{\partial t_{1}} = \mathbf{A} \mathbf{R}_{X}(t_{1}, t_{2}) + \\
+ \mathbf{B} \mathbf{R}_{FX}(t_{1}, t_{2}) \\
\mathbf{R}_{X}(0, t_{2}) = \mathbf{X}_{0} \mu^{T}(t_{2})
\end{cases} (10)$$

If the initial condition of the system (9) is a vector of random variables, it is necessary to find the initial condition of the system (9). It can be obtained by multiplying the equation (1) by  $\mathbf{X}_0$  and substituting t to  $t_2$  (assuming that the initial condition is independent of forcing):

$$\begin{cases}
\frac{\partial \mathbf{R}_{X}(0,t_{2})}{\partial t_{2}} = \mathbf{R}_{X}(0,t_{2})\mathbf{A}^{T} + \\
+ \mu_{X_{0}}\mu_{F}^{T}(t_{2})\mathbf{B}^{T} \cdot \\
\mathbf{R}_{X}(0,0) = E\left[\mathbf{X}_{0}\mathbf{X}_{0}^{T}\right]
\end{cases} (11)$$

Covariance and variance of the process  $\mathbf{X}(t)$  can be obtained from the relationship:

$$\mathbf{C}_{X}(t_{1},t_{2}) = \mathbf{R}_{X}(t_{1},t_{2}) - \mu_{X}(t_{1})\mu_{X}^{T}(t_{2}), \quad (12)$$

$$\sigma_{Y}^{2}(t) = \mathbf{C}_{Y}(t,t). \quad (13)$$

Applying the expectation operator to equation (2) one can obtain the equation for the expected values of the process  $\mathbf{Y}(t)$ :

$$\mu_{Y}(t) = \mathbf{C}\mu_{X}(t) + \mathbf{D}\mu_{F}(t). \tag{14}$$

Cross correlation of the processes  $\mathbf{F}(t)$  and  $\mathbf{Y}(t)$  is the function:

$$E[\mathbf{F}(t_1)\mathbf{Y}^T(t_2)] = E[\mathbf{F}(t_1)\mathbf{X}^T(t_2)]\mathbf{C}^T + E[\mathbf{F}^T(t_1)\mathbf{F}(t_2)]\mathbf{D}^T,$$
(15)

which means:

$$\mathbf{R}_{FY}(t_1, t_2) = \mathbf{R}_{FX}(t_1, t_2)\mathbf{C}^T + \mathbf{R}_F(t_1, t_2). \quad (16)$$

Autocorrelation of the process  $\mathbf{Y}(t)$  is the function:

$$\mathbf{R}_{Y}(t_{1},t_{2}) = E\left[\mathbf{Y}(t_{1})\mathbf{Y}^{T}(t_{2})\right]. \tag{17}$$

Taking into account the identity:

$$\mathbf{X}(t_1)\mathbf{F}^T(t_2) = (\mathbf{F}(t_2)\mathbf{X}^T(t_1))^T.$$
 (18)

The equation (17) can be expressed as:

$$\mathbf{R}_{Y}(t_{1},t_{2}) = \mathbf{C}\mathbf{R}_{X}(t_{1},t_{2})\mathbf{C}^{T} +$$

$$+ \mathbf{C}\mathbf{R}_{FX}(t_{2},t_{1})\mathbf{D}^{T} + \mathbf{D}\mathbf{R}_{FX}(t_{1},t_{2})\mathbf{C}^{T} + . (19)$$

$$+ \mathbf{C}\mathbf{R}_{F}(t_{1},t_{2})\mathbf{D}^{T}.$$

Covariance and variance of the process Y(t) can be obtained from the relationship:

$$\mathbf{C}_{Y}\left(t_{1}, t_{2}\right) = \mathbf{R}_{Y}\left(t_{1}, t_{2}\right) - \mu_{Y}\left(t_{1}\right)\mu_{Y}^{T}\left(t_{2}\right), \quad (20)$$

$$\sigma_Y^2(t) = \mathbf{C}_Y(t,t). \tag{21}$$

#### 4. Example

The series RLC circuit is supplied by the ideal voltage source U(t):

$$U(t) = \sin(t + \phi) \tag{22}$$

where  $\phi$  is a random variable with known probability density function:

$$f_{\phi}(x) = \frac{1}{\pi} (H(x) - H(x - \pi))$$
 (23)

where H(x) is the Heaviside steep function. The probability density function of random variable  $\phi$  is shown in Fig 1.

The mean value of the force process U(t) is given:

$$\mu_{U}(t) = \mathbf{E}[U(t)] =$$

$$= \int_{-\infty}^{\infty} \sin(t+x) f_{\phi}(x) dx = \frac{2}{\pi} \cos(t).$$
(24)

The mean value of the force process U(t) is shown in Fig. 2. The variance of the force process U(t) is given:

$$\sigma_U^2(t) = \mathbf{E} \left[ U^2(t) \right] - \mu_U^2(t) =$$

$$= \int_{-\infty}^{\infty} \sin^2(t+x) f_{\phi}(x) dx - \mu_U^2(t) = . \quad (25)$$

$$= \frac{1}{2} - \frac{4}{\pi^2} \cos^2(t).$$

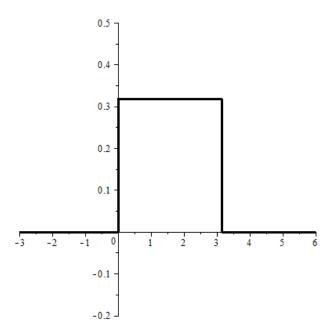


Fig. 1. Probability density function of random variable  $\phi$ .

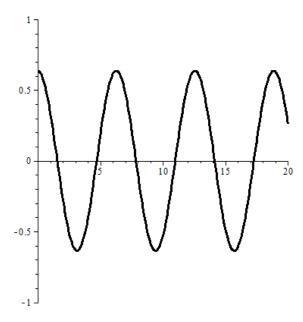


Fig. 2. Mean value of the force process U(t).

Autocorrelation  $\mathbf{R}_F(t_1,t_2)=\mathbf{R}_U(t_1,t_2)$  of the force processes is given by the equation:

$$\mathbf{R}_{U}(t_{1},t_{2}) = \mathbf{E}\left[U(t_{1})U(t_{2})\right] =$$

$$= \sin(t_{1}+t_{2})/4 + \pi\cos(t_{1})\cos(t_{2})/2 +$$

$$+ \pi\sin(t_{1})\sin(t_{2})/2 - \sin(t_{1})\cos(t_{2})/4 -$$

$$-\cos(t_{1})\sin(t_{2})/4.$$
(26)

Autocorrelation  $\mathbf{R}_U(t_1,t_2)$  is used to determine the cross correlation of the force and response (33).

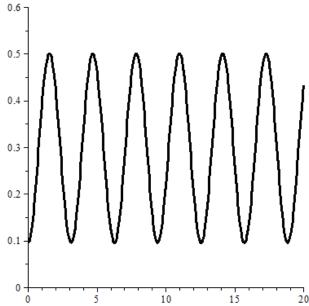


Fig. 3. Variance of the force process U(t).

For simplicity it is assumed that R=L=C=1 and  $I(0)=U_C(0)=0$ . The state equation of the RLC system is given:

$$\left| \frac{\frac{d}{dt}I(t)}{\frac{d}{dt}U_{C}(t)} \right| = \begin{bmatrix} -R/L & -1/L \\ 1/C & 0 \end{bmatrix} \begin{bmatrix} I(t) \\ U_{C}(t) \end{bmatrix} + \left[ \frac{1/L}{0} \right] [U(t)], \tag{27}$$

where:

$$\mathbf{X}(t) = \begin{bmatrix} I(t) \\ U_C(t) \end{bmatrix}, \tag{28}$$

Applying the formula (3) to the equation (27), one can obtain the expected value of the output process:

$$\begin{bmatrix}
\frac{d}{dt}\mu_{I}(t) \\
\frac{d}{dt}\mu_{U_{C}}(t)
\end{bmatrix} = \begin{bmatrix} -1 & -1 \\ 1 & 0 \end{bmatrix} \begin{bmatrix} \mu_{I}(t) \\ \mu_{U_{C}}(t) \end{bmatrix} + \\
+ \begin{bmatrix} 1 \\ 0 \end{bmatrix} \begin{bmatrix} \frac{2}{\pi}\cos(t) \end{bmatrix}.$$
(29)

The solution of the equation (29) is given by the formulas:

$$\mu_{I}(t) = \frac{2\sqrt{3}}{3\pi} \sin(\sqrt{3}t/2)e^{-t/2} - \frac{2}{\pi}\cos(\sqrt{3}t/2)e^{-t/2} + \frac{2}{\pi}\cos(t),$$

$$\mu_{U_{C}}(t) = -\frac{4\sqrt{3}}{3\pi}\sin(\sqrt{3}t/2)e^{-t/2} + \frac{2}{\pi}\sin(t). (31)$$

The cross correlation of the force and response is the function:

$$\mathbf{R}_{FX}(t_1, t_2) = \left[ \mathbf{R}_{UI}(t_1, t_2) \mathbf{R}_{UU_C}(t_1, t_2) \right]. \quad (32)$$

Applying formula (7) to the equation (27), one can obtain the cross correlation of the force and response:

$$\begin{cases}
\frac{\partial R_{UI}(t_{1},t_{2})}{\partial t_{2}} = -R_{UI}(t_{1},t_{2}) - R_{UU_{C}}(t_{1},t_{2}) + \\
+ R_{U}(t_{1},t_{2}) \\
\frac{\partial R_{UU_{C}}(t_{1},t_{2})}{\partial t_{2}} = R_{UI}(t_{1},t_{2}) \\
R_{UI}(t_{1},0) = R_{UU_{C}}(t_{1},0) = 0
\end{cases} (33)$$

The solution of the equations (33) is given by the formulas:

$$\mathbf{R}_{UI}(t_1, t_2) = \frac{\pi}{6} \left( 3\cos(t_1 - t_2) + \frac{\pi}{6} \left( 3\cos(t_1 - t_2) + \frac{\pi}{6} \left( 3\cos(t_1) \sin(\sqrt{3}t_2/2) e^{-t_2/2} - \frac{\pi}{6} \cos(t_1) \sin(\sqrt{3}t_2/2) e^{-t_2/2} - \frac{\pi}{6} \cos(t_1) \cos(\sqrt{3}t_2/2) e^{-t_2/2} \right) \right)$$

$$\mathbf{R}_{UI}(t_1, t_2) = \frac{\pi}{6} \left( 3\sin(t_1 - t_2) + \frac{\pi}{6} \right)$$

$$(34)$$

$$\mathbf{R}_{UI}(t_1, t_2) = \frac{\pi}{6} \left( 3\sin(t_1 - t_2) + \frac{\pi}{6} \right)$$

$$\mathbf{R}_{UU_{C}}(t_{1},t_{2}) = \frac{-\pi}{6} \left(3\sin(t_{1}-t_{2}) + 2\sqrt{3}\cos(t_{1})\sin(\sqrt{3}t_{2}/2)e^{-t_{2}/2} - \sqrt{3}\sin(t_{1})\sin(\sqrt{3}t_{2}/2)e^{-t_{2}/2} - 3\sin(t_{1})\cos(\sqrt{3}t_{2}/2)e^{-t_{2}/2}\right).$$
(35)

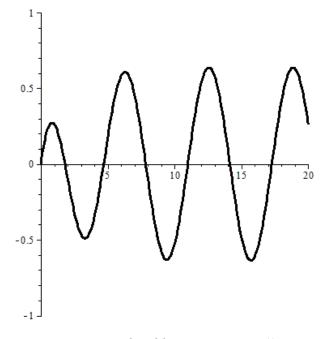


Fig. 4. Mean value of the response process I(t).

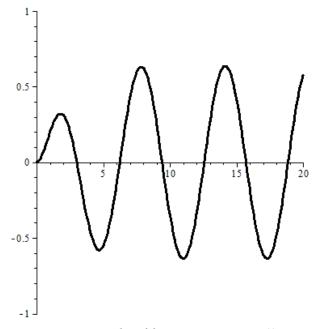


Fig. 5. Mean value of the response process  $U_c(t)$ .

The autocorelation of the response is shown in the Fig. 6, 7, 8, 9.

The autocorrelation of the response is the function:

$$\mathbf{R}_{X}(t_{1}, t_{2}) = \begin{bmatrix} R_{I}(t_{1}, t_{2}) & R_{IU_{C}}(t_{1}, t_{2}) \\ R_{U_{C}I}(t_{1}, t_{2}) & R_{U_{C}}(t_{1}, t_{2}) \end{bmatrix}.$$
(36)

In the same way, applying the formula (10) to the equation (27), one can obtain the autocorrelation  $\mathbf{R}_{X}(t_{1},t_{2})$  of the output process:

$$\frac{\partial R_{I}(t_{1},t_{2})}{\partial t_{1}} = -R_{I}(t_{1},t_{2}) - R_{U_{C}I}(t_{1},t_{2}) + R_{U_{I}}(t_{1},t_{2}) + R_{U_{I}}(t_{1},t_{2}) + R_{U_{I}}(t_{1},t_{2}) - R_{U_{C}}(t_{1},t_{2}) + R_{U_{C}}(t_{1},t_{2}) - R_{U_{C}}(t_{1},t_{2}) + R_{UU_{C}}(t_{1},t_{2}) + R_{UU_{C}}(t_{1},t_{2})$$

$$\frac{\partial R_{U_{C}I}(t_{1},t_{2})}{\partial t_{1}} = R_{I}(t_{1},t_{2})$$

$$\frac{\partial R_{U_{C}}(t_{1},t_{2})}{\partial t_{1}} = R_{IU_{C}}(t_{1},t_{2})$$

$$\frac{\partial R_{U_{C}}(t_{1},t_{2})}{\partial t_{1}} = R_{IU_{C}}(t_{1},t_{2})$$

$$R_{I}(0,t_{2}) = R_{IU_{C}}(0,t_{2}) = 0$$

$$R_{U_{C}I}(0,t_{2}) = R_{U_{C}}(0,t_{2}) = 0$$

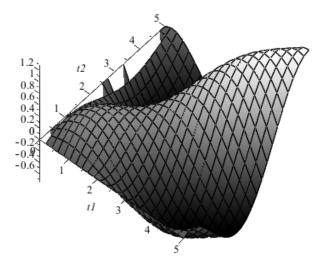


Fig. 6. Autocorrelation of the responseprocess I(t).

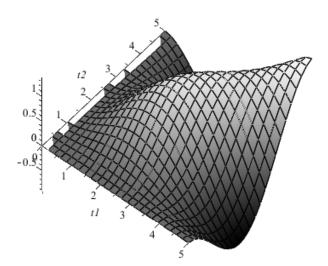


Fig. 7. Autocorrelation of the response process  $U_C(t)$ .

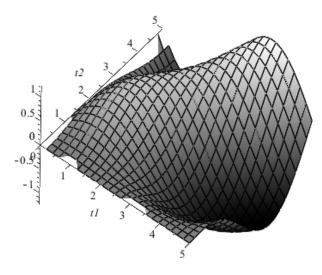


Fig. 8. Correlation of the response processes I(t) and  $U_C(t)$ .

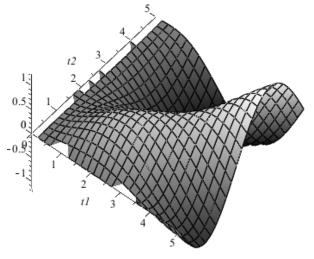


Fig. 9. Correlation of the response processes  $U_C(t)$  and I(t).

#### 5. Conclusion

In this paper the method of the problem of the moment determination for complex deterministic and dynamical systems of the n-th order with random excitations has been described. It enables converting the problem of the n-th order stochastic differential equation solving into the problem of ordinary differential equations have been defined in terms of the stochastic process moments and as a result their solution is relatively simple.

Contrary to the previous works the proposed method can be applied for systems of any order.

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# ДИНАМІЧНІ ЛІНІЙНІ СИСТЕМИ N-го ПОРЯДКУ ЗА ВИПАДКОВИХ УМОВ

## Северин Мазуркевич, Януш Вальчак

Розглянуто лінійну динамічну стохастичну модель п-го порядку, що описується стохастичним рівнянням стану. Показано метод визначення імовірнісних характеристик стохастичного процесу, які є розв'язком такого рівняння. Ці характеристики, як, наприклад, середні значення та кореляційні функції, визначаються додатковими умовами — детермінованими системами звичайних диференційних рівнянь.



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